

Appl. No. 10/707,560  
Amtd. dated January 26, 2006  
Reply to Office action of November 30, 2005

**Amendments to the Claims:**

This listing of claims will replace all prior versions and listings of claims in the application:

**Listing of Claims:**

5   Claims 1-9 (cancelled)

Claim 10 (previously presented) A method of repairing electrode pattern defects of a plasma display panel (PDP) comprising:

10                 performing an inspection process to determine a pit defect and a salient defect of the plasma display panel;

               performing a first one-step repairing process for filling the pit defect; and

               performing a second repairing process for removing the salient defect.

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Claim 11 (original) The method of claim 10, wherein the electrode pattern is composed of a transparent conductive material or a metal conductive material.

20   Claim 12 (previously presented) The method of claim 10, wherein the pit defect comprises a hole, an incomplete connection, or a broken connection.

25   Claim 13 (previously presented) The method of claim 10, wherein the first one-step repairing process fills the pit defect with a conductive paste.

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**Claim 14 (original)** The method of claim 13, wherein the conductive paste is selected from a group consisting of silver paste, ITO paste, IZO paste, gold paste, and silver glue.

5   **Claim 15 (previously presented)** The method of claim 13, wherein the pit defect is completely filled up in the first one-step repairing process.

10   **Claim 16 (previously presented)** The method of claim 13, wherein the pit defect is partially filled up in the first one-step repairing process.

**Claim 17 (cancelled)**

15   **Claim 18 (previously presented)** The method of claim 10, wherein the second repairing process removes the salient defect by means of a laser beam.

20   **Claim 19 (original)** The method of claim 10, wherein the inspection process comprises an optical inspection process or an electrical inspection process, and the electrode pattern comprises a sustain electrode pattern, a bus electrode pattern, or an address electrode pattern.